Abstracts

Barium Tetratitanate MIC Technology

Y.S. Lee, W.J. Getsinger and L.R. Sparrow. "Barium Tetratitanate MIC Technology." 1979 Transactions on Microwave Theory and Techniques 27.7 (Jul. 1979 [T-MTT]): 655-660.

Experimental results on BaTi/sub 4/O/sub 9/ microwave integrated circuit (MIC) characteristics, including microstrip dispersion and loss, have shown excellent agreement with the theoretical predictions. Precision measurements of temperature stability were conducted at 14 GHz. The high dielectric constant (epsilon/sub r/ = 37) and its negative temperature coefficient can be used in specialized MIC's for application to advanced microwave subsystems.

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